



ALPHA & OMEGA
SEMICONDUCTOR

AOT2916L/AOTF2916L 100V N-Channel MOSFET

General Description

The AOT2916L & AOTF2916L uses trench MOSFET technology that is uniquely optimized to provide the most efficient high frequency switching performance. Both conduction and switching power losses are minimized due to an extremely low combination of $R_{DS(ON)}$, Ciss and Coss. This device is ideal for boost converters and synchronous rectifiers for consumer, telecom, industrial power supplies and LED backlighting.

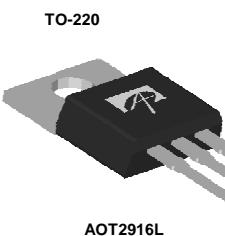
Product Summary

V_{DS}	100V
I_D (at $V_{GS}=10V$)	23A / 17A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 34mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$)	< 43.5mΩ

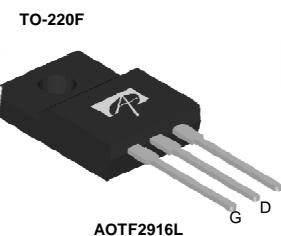
100% UIS Tested
100% R_g Tested



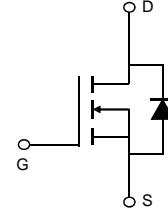
Top View



TO-220



TO-220F



AOT2916L

AOTF2916L

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	AOT2916L	AOTF2916L	Units
Drain-Source Voltage	V_{DS}	100		V
Gate-Source Voltage	V_{GS}	± 20		V
Continuous Drain Current	$I_C=25^\circ\text{C}$	I_D	23	A
Current			16	
Pulsed Drain Current ^C	I_{DM}	50		
Continuous Drain Current	$T_C=25^\circ\text{C}$	I_{DSM}	5	A
Current			4	
Avalanche Current ^C	I_{AS}	8		A
Avalanche energy L=0.1mH ^C	E_{AS}	3		mJ
Power Dissipation ^B	$T_C=25^\circ\text{C}$	P_D	41.5	W
			20.5	
Power Dissipation ^A	$T_A=25^\circ\text{C}$	P_{DSM}	2.1	W
			1.3	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175		°C

Thermal Characteristics

Parameter	Symbol	AOT2916L	AOTF2916L	Units
Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$	$R_{\theta JA}$	15	15	°C/W
Maximum Junction-to-Ambient ^{A D} Steady-State		60	60	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	3.6	6.4	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	100			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=100\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			± 100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.6	2	2.7	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	50			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=10\text{A}$ $T_J=125^\circ\text{C}$		28 51	34 62	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=3\text{A}$		35	43.5	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=10\text{A}$		28		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.75	1	V
I_S	Maximum Body-Diode Continuous Current				23	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=50\text{V}, f=1\text{MHz}$		870		pF
C_{oss}	Output Capacitance			68		pF
C_{rss}	Reverse Transfer Capacitance			3.5		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		7		Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=50\text{V}, I_D=10\text{A}$		12.5	20	nC
$Q_g(4.5\text{V})$	Total Gate Charge			5.5	10	nC
Q_{gs}	Gate Source Charge			2.5		nC
Q_{gd}	Gate Drain Charge			2		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=50\text{V}, R_L=5\Omega, R_{\text{GEN}}=3\Omega$		7.5		ns
t_r	Turn-On Rise Time			3.5		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			23		ns
t_f	Turn-Off Fall Time			5.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=10\text{A}, dI/dt=500\text{A}/\mu\text{s}$		20		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=10\text{A}, dI/dt=500\text{A}/\mu\text{s}$		88		nC

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$. The Power dissipation P_{DSM} is based on $R_{\theta JA}$ and the maximum allowed junction temperature of 150° C . The value in any given application depends on the user's specific board design, and the maximum temperature of 175° C may be used if the PCB allows it.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=175^\circ\text{ C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=175^\circ\text{ C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{ C}$.

D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.

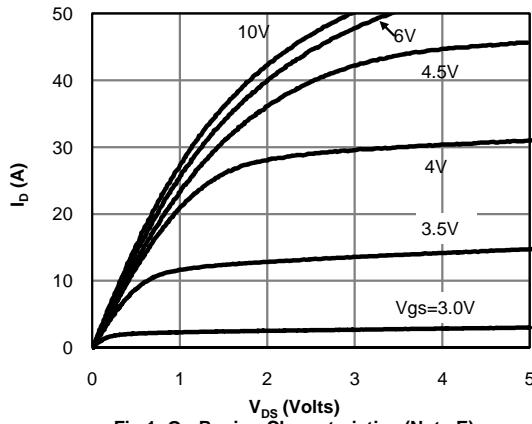
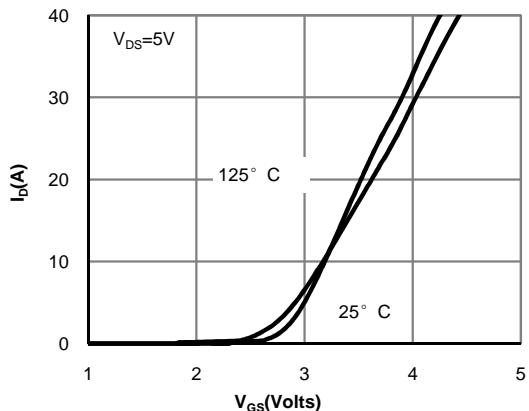
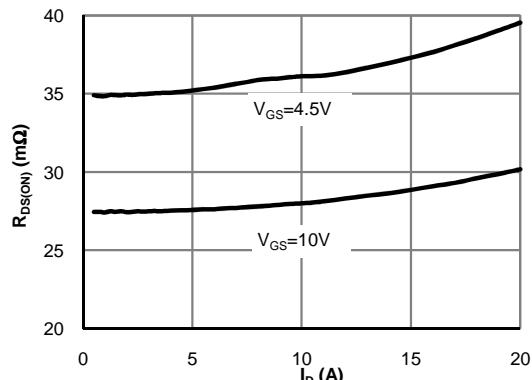
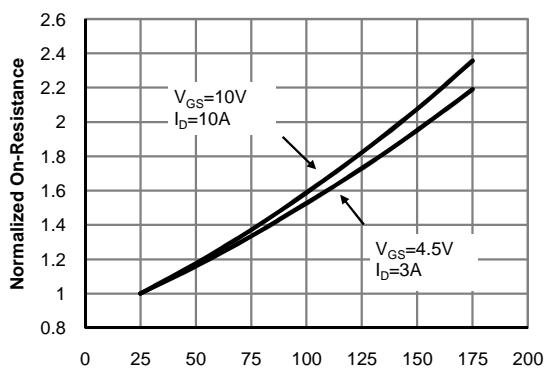
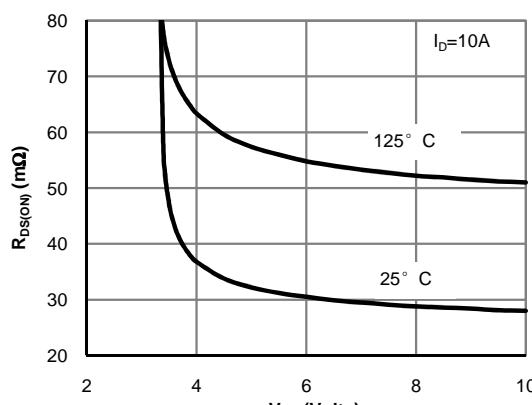
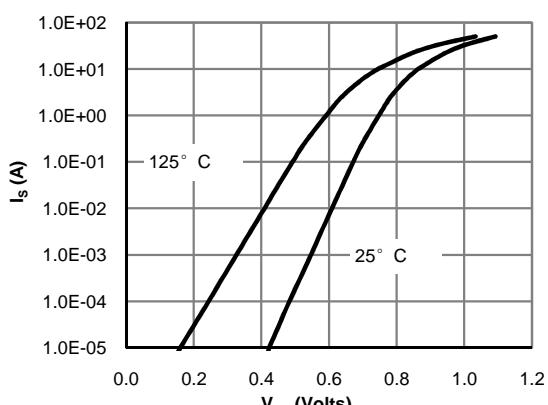
E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

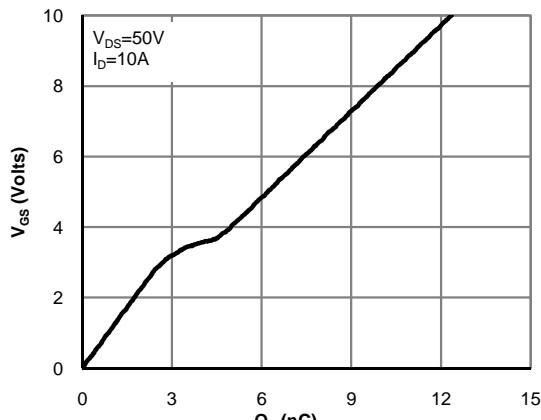
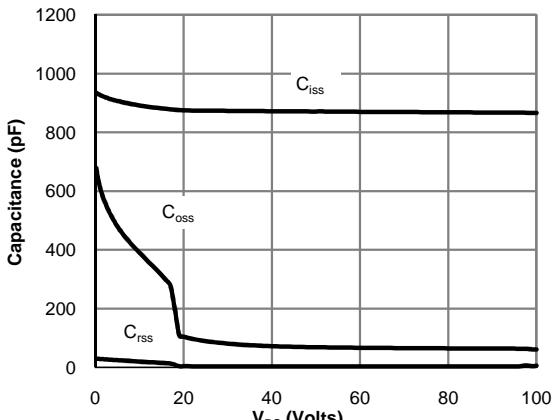
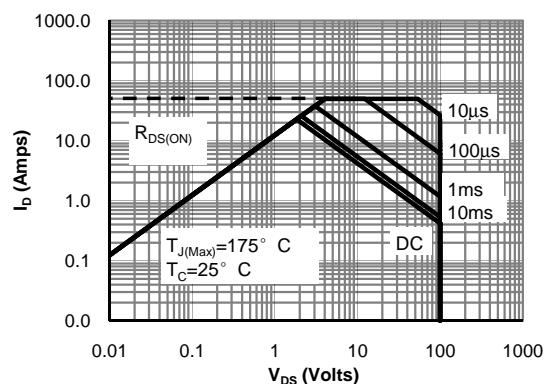
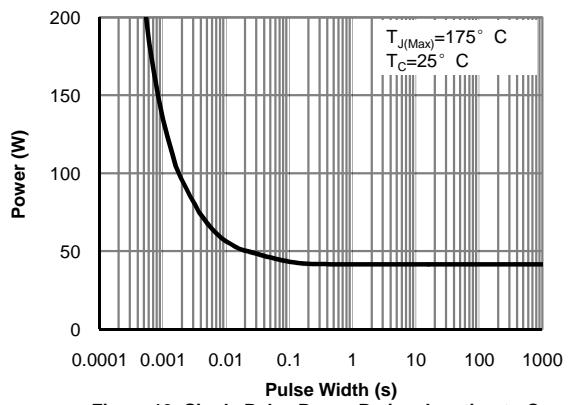
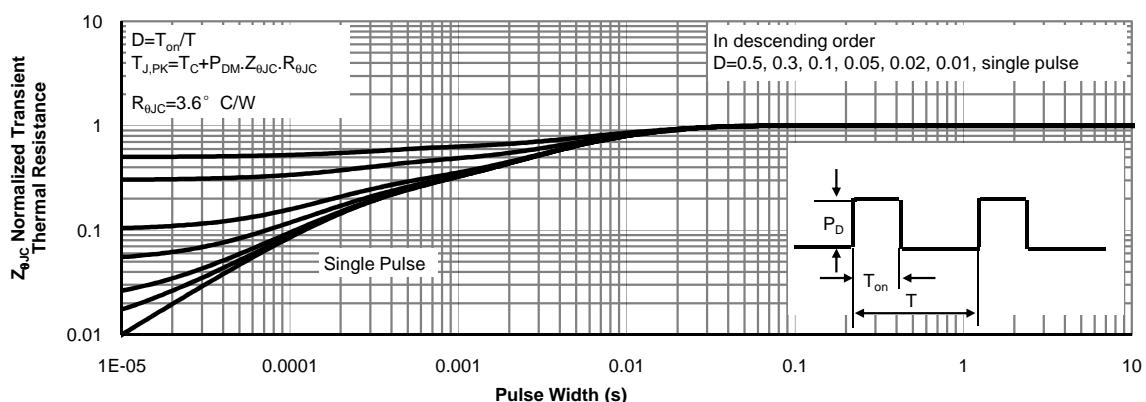
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=175^\circ\text{ C}$. The SOA curve provides a single pulse rating.

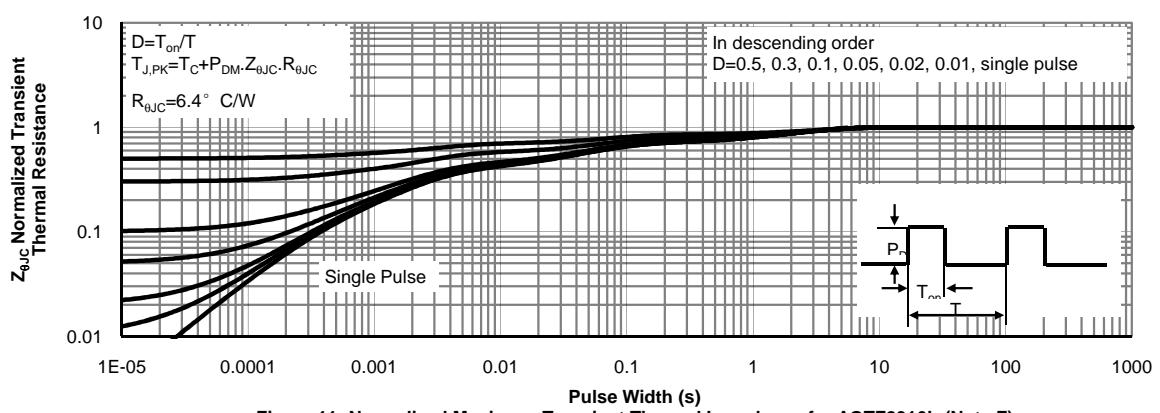
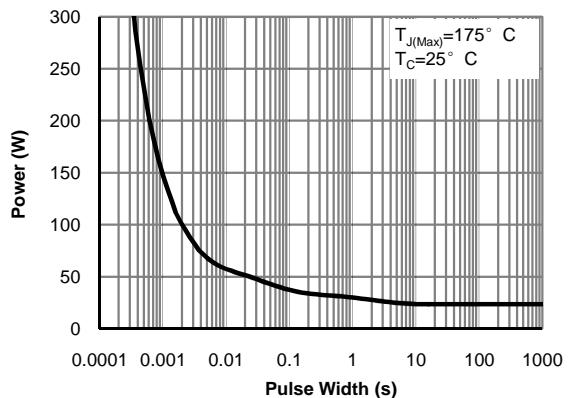
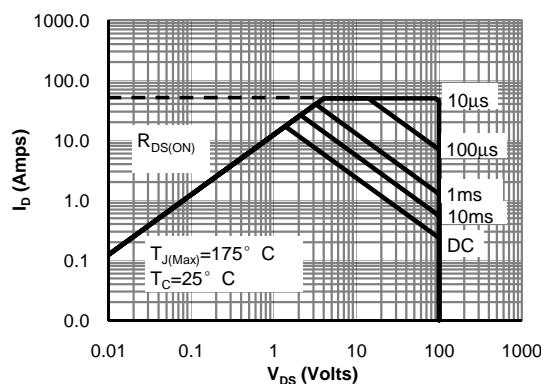
G. The maximum current limited by package.

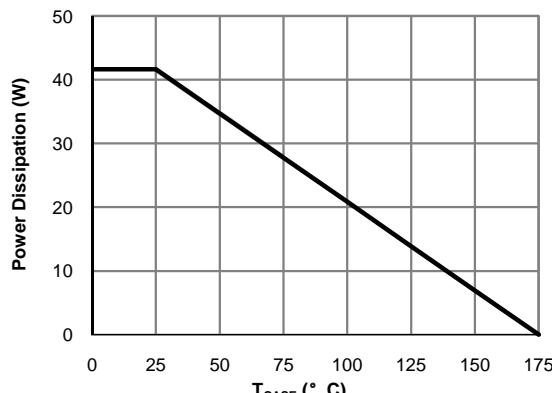
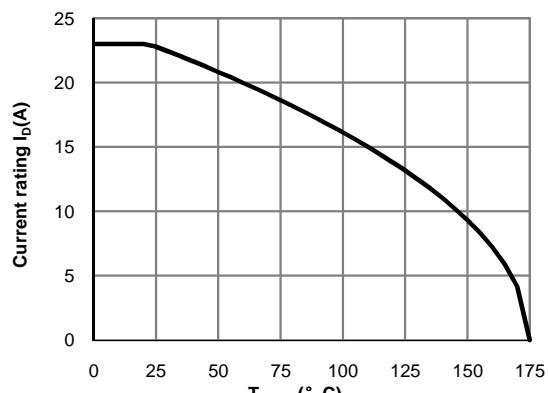
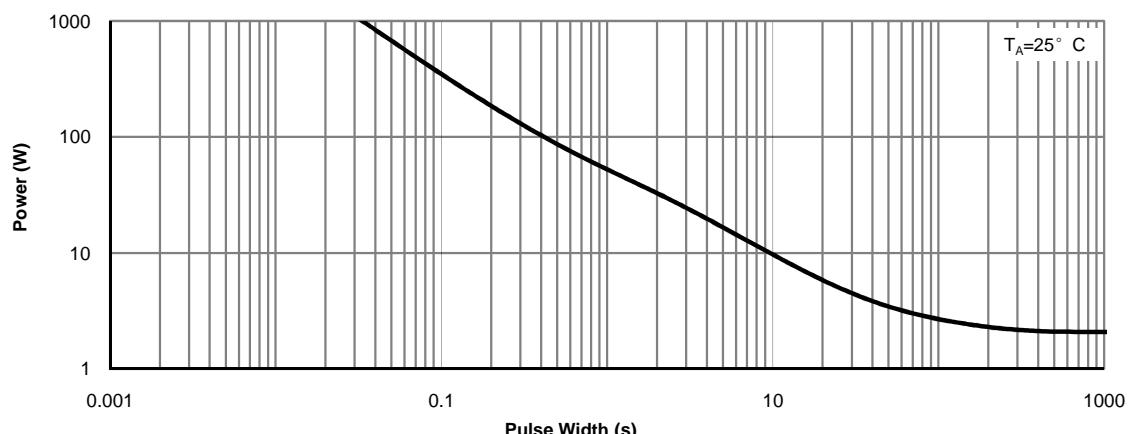
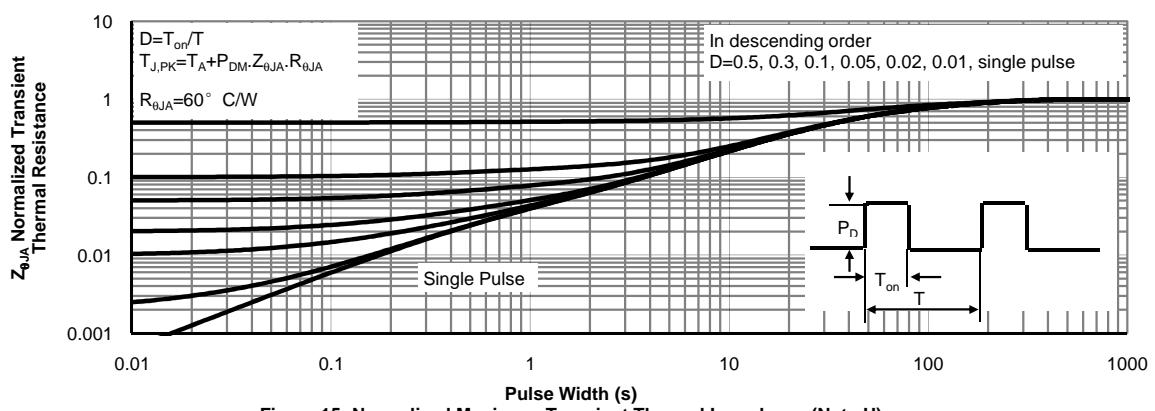
H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$.

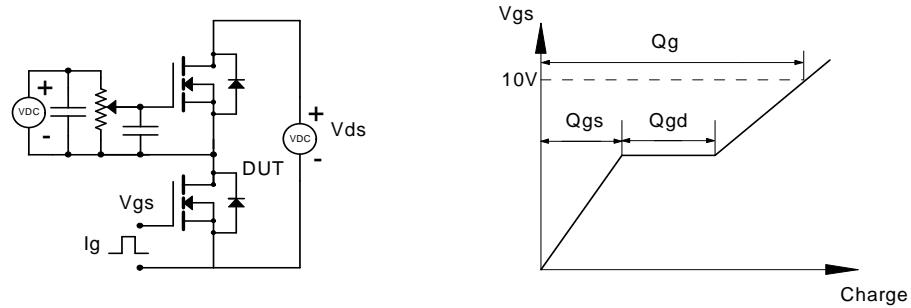
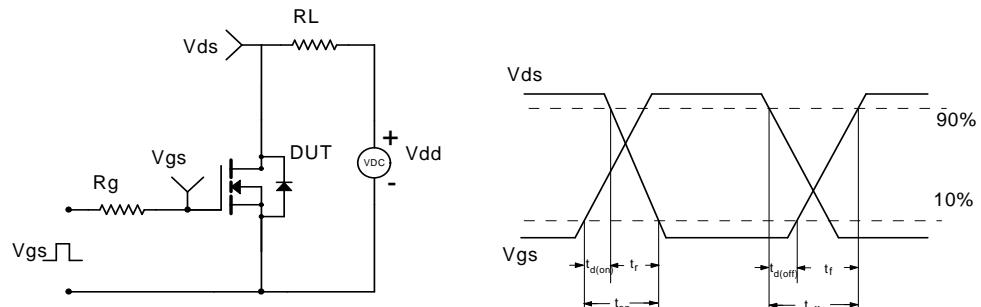
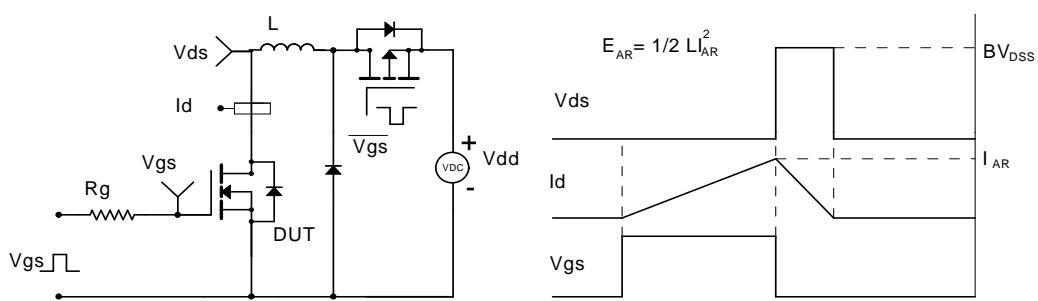
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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area for AOT2916L (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Case for AOT2916L (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance for AOT2916L (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


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Figure 12: Power De-rating (Note F)

Figure 13: Current De-rating (Note F)

Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
